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**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**  
**In re PATENT APPLICATION OF**

NAVARRO y KOREN et al.

Group Art Unit: UNKNOWN

Application No. TO BE ASSIGNED

Examiner: UNKNOWN

Filed: September 22, 2003

Title: ALIGNMENT SYSTEM AND METHODS FOR LITHOGRAPHIC SYSTEMS  
USING AT LEAST TWO WAVELENGTHS

\* \* \* \* \*

September 22, 2003

**PRELIMINARY AMENDMENT**

Hon. Commissioner of Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Prior to the initial examination of the above-identified application, please amend the application as follows.

This Preliminary Amendment is being presented in the REVISED FORMAT approved in February, 2003.